



## Achieving Application-reliable GaN Devices



### Keynote speaker:

Dr. Sandeep Bahl

Distinguished Member Of Technical Staff,  
Manager, High Voltage Power Solutions  
Texas Instruments



**Sandeep Bahl** has a solid industrial track record in semiconductor technologies with meaningful contributions to both Silicon and III-V technologies. He has hands-on experience with technology development, management, IP generation, and publication. Sandeep co-invented the direct-drive architecture used in TI GaN products. His present focus is to bring reliable GaN products to market. He has done pioneering work in application reliability, leading to both increased market adoption for the GaN industry and reliable GaN products for TI. Sandeep is co-chair of the JEDEC JC70 GaN reliability task group and led the first JEDEC GaN reliability guideline, JEP180. Sandeep has also served in chair roles for wide bandgap technology and reliability at several IEEE conferences. He graduated with a PhD in Electrical Engineering from the Massachusetts Institute of Technology.